PSMN057-200B

N-channel TrenchMOS SiliconMAX standard level FET

Rev. 02 — 14 December 2010

Product data sheet

1. Product profile

1.1 General description

SiliconMAX standard level N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOS technology. This product is designed and qualified for use in computing, communications, consumer and industrial applications only.

1.2 Features and benefits

- Higher operating power due to low thermal resistance
- Low conduction losses due to low on-state resistance
- Suitable for high frequency applications due to fast switching characteristics

1.3 Applications

DC-to-DC converters

Switched-mode power supplies

1.4 Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V_{DS}	drain-source voltage	T _j ≥ 25 °C; T _j ≤ 175 °C	-	-	200	V
I_D	drain current	T _{mb} = 25 °C	-	-	39	Α
P _{tot}	total power dissipation		-	-	250	W
Static chara	acteristics					
R _{DSon}	drain-source on-state resistance	$V_{GS} = 10 \text{ V}; I_D = 17 \text{ A}; T_j = 25 \text{ °C}$	-	41	57	mΩ
Dynamic cl	naracteristics					
Q_{GD}	gate-drain charge	$V_{GS} = 10 \text{ V}; I_D = 39 \text{ A};$ $V_{DS} = 160 \text{ V}; T_j = 25 \text{ °C}$	-	37	50	nC



2. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	G	gate		_
2	D	drain	mb	D D
3	S	source		
mb	D	mounting base; connected to drain	1 3	mbb076 S
			SOT404 (D2PAK)	

3. Ordering information

Table 3. Ordering information

Type number	Package		
	Name	Description	Version
PSMN057-200B	D2PAK	plastic single-ended surface-mounted package (D2PAK); 3 leads (one lead cropped)	SOT404

4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

$\begin{array}{llllllllllllllllllllllllllllllllllll$						
$\begin{array}{c ccccccccccccccccccccccccccccccccccc$	Symbol	Parameter	Conditions	Min	Max	Unit
$V_{GS} \qquad \text{gate-source voltage} \qquad \qquad -20 \qquad 20$ $I_D \qquad \text{drain current} \qquad \frac{T_{mb} = 100 ^{\circ}\text{C}}{T_{mb} = 25 ^{\circ}\text{C}} \qquad - \qquad 39$ $I_{DM} \qquad \text{peak drain current} \qquad \text{pulsed; } T_{mb} = 25 ^{\circ}\text{C} \qquad - \qquad 156$ $P_{tot} \qquad \text{total power dissipation} \qquad T_{mb} = 25 ^{\circ}\text{C} \qquad - \qquad 250$ $T_{stg} \qquad \text{storage temperature} \qquad -55 \qquad 175$ $T_j \qquad \text{junction temperature} \qquad -55 \qquad 175$ $Source-drain \ diode$ $I_S \qquad \text{source current} \qquad T_{mb} = 25 ^{\circ}\text{C} \qquad - \qquad 39$ $I_{SM} \qquad \text{peak source current} \qquad pulsed; T_{mb} = 25 ^{\circ}\text{C} \qquad - \qquad 39$ $I_{SM} \qquad \text{peak source current} \qquad \text{pulsed; } T_{mb} = 25 ^{\circ}\text{C} \qquad - \qquad 156$ $Avalanche \ ruggedness$ $E_{DS(AL)S} \qquad \text{non-repetitive drain-source} \qquad V_{GS} = 10 V; T_{j(init)} = 25 ^{\circ}\text{C}; I_D = 35 \text{A}; \\ v_{sup} \leq 50 V; \text{unclamped; } t_p = 100 \mu \text{s}; \\ R_{GS} = 50 \Omega$ $I_{AS} \qquad \text{non-repetitive avalanche current} \qquad V_{sup} \leq 50 V; V_{GS} = 10 V; T_{j(init)} = 25 ^{\circ}\text{C}; - \qquad 35$	V_{DS}	drain-source voltage	T _j ≥ 25 °C; T _j ≤ 175 °C	-	200	V
$\begin{array}{c} I_{D} \\ \\ I_{DM} \\ \\ \\ I_{DM} \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\$	V_{DGR}	drain-gate voltage	$T_j \ge 25 \text{ °C}; T_j \le 175 \text{ °C}; R_{GS} = 20 \text{ k}\Omega$	-	200	V
$T_{mb} = 25 ^{\circ}\text{C} \qquad - 39$ $I_{DM} \qquad \text{peak drain current} \qquad \text{pulsed; } T_{mb} = 25 ^{\circ}\text{C} \qquad - 156$ $P_{tot} \qquad \text{total power dissipation} \qquad T_{mb} = 25 ^{\circ}\text{C} \qquad - 250$ $T_{stg} \qquad \text{storage temperature} \qquad -55 \qquad 175$ $T_{j} \qquad \text{junction temperature} \qquad -55 \qquad 175$ $Source-drain \ diode$ $I_{S} \qquad \text{source current} \qquad T_{mb} = 25 ^{\circ}\text{C} \qquad - 39$ $I_{SM} \qquad \text{peak source current} \qquad \text{pulsed; } T_{mb} = 25 ^{\circ}\text{C} \qquad - 156$ $Avalanche \ ruggedness$ $E_{DS(AL)S} \qquad \text{non-repetitive drain-source} \qquad V_{GS} = 10 \text{V; } T_{j(init)} = 25 ^{\circ}\text{C; } I_{D} = 35 \text{A;} \qquad - 300$ $V_{sup} \leq 50 \text{V; unclamped; } t_{p} = 100 \mu\text{s;} \qquad R_{GS} = 50 \Omega$ $I_{AS} \qquad \text{non-repetitive avalanche current} \qquad V_{sup} \leq 50 \text{V; } V_{GS} = 10 \text{V; } T_{j(init)} = 25 ^{\circ}\text{C;} \qquad - 35$	V_{GS}	gate-source voltage		-20	20	V
I_{DM} peak drain current pulsed; T_{mb} = 25 °C - 156 T_{stg} total power dissipation T_{mb} = 25 °C - 250 T_{stg} storage temperature -55 175 T_{j} junction temperature -55 175 T_{j} junction temperature T _{mb} = 25 °C - 39 T_{stg} source current T_{mb} = 25 °C - 39 T_{stg} peak source current pulsed; T_{mb} = 25 °C - 156 T_{stg} non-repetitive drain-source T_{mb} = 25 °C - 156 T_{stg} non-repetitive drain-source T_{mb} = 25 °C; T_{stg} non-repetitive drain-source T_{stg} non-repetitive drain-source T_{stg} non-repetitive drain-source T_{stg} non-repetitive avalanche current T_{stg} = 10 V; T_{stg} = 10 V; T_{stg} = 100 μs; T_{stg} = 10 V; T_{stg} = 10 V; T_{stg} = 100 μs; T_{stg} = 10 V; T_{stg} = 100 μs; T_{stg} = 10 V; T_{stg} =	I _D	drain current	T _{mb} = 100 °C	-	27.5	Α
$\begin{array}{cccccccccccccccccccccccccccccccccccc$			T _{mb} = 25 °C	-	39	Α
$\begin{array}{cccccccccccccccccccccccccccccccccccc$	I _{DM}	peak drain current	pulsed; T _{mb} = 25 °C	-	156	Α
$T_{j} \qquad \text{junction temperature} \qquad \qquad -55 \qquad 175 \\ \hline \textbf{Source-drain diode} \\ \hline I_{S} \qquad \text{source current} \qquad T_{mb} = 25 ^{\circ}\text{C} \qquad - \qquad 39 \\ \hline I_{SM} \qquad \text{peak source current} \qquad \text{pulsed; } T_{mb} = 25 ^{\circ}\text{C} \qquad - \qquad 156 \\ \hline \textbf{Avalanche ruggedness} \\ \hline E_{DS(AL)S} \qquad \text{non-repetitive drain-source} \qquad V_{GS} = 10 \text{V; } T_{j(init)} = 25 ^{\circ}\text{C; } I_{D} = 35 \text{A;} \qquad - \qquad 300 \\ v_{sup} \leq 50 \text{V; unclamped; } t_{p} = 100 \text{µs;} \\ R_{GS} = 50 \Omega \\ \hline I_{AS} \qquad \text{non-repetitive avalanche current} \qquad V_{sup} \leq 50 \text{V; } V_{GS} = 10 \text{V; } T_{j(init)} = 25 ^{\circ}\text{C;} \qquad - \qquad 35 \\ \hline \end{tabular}$	P _{tot}	total power dissipation	T _{mb} = 25 °C	-	250	W
	T _{stg}	storage temperature		-55	175	°C
$\begin{array}{c ccccccccccccccccccccccccccccccccccc$	Tj	junction temperature		-55	175	°C
$I_{SM} \qquad \text{peak source current} \qquad \text{pulsed; T}_{mb} = 25 \text{ °C} \qquad - \qquad 156$	Source-drain	n diode				
	Is	source current	T _{mb} = 25 °C	-	39	Α
$\begin{array}{c} E_{DS(AL)S} & \text{non-repetitive drain-source} \\ \text{avalanche energy} & V_{GS} = 10 \text{ V}; T_{j(\text{init})} = 25 \text{ °C}; I_D = 35 \text{ A}; \\ V_{sup} \leq 50 \text{ V}; \text{ unclamped}; t_p = 100 \mu\text{s}; \\ R_{GS} = 50 \Omega \\ \end{array}$	I _{SM}	peak source current	pulsed; T _{mb} = 25 °C	-	156	Α
avalanche energy $V_{sup} \leq 50 \text{ V; unclamped; } t_p = 100 \mu\text{s;}$ $R_{GS} = 50 \Omega$ $I_{AS} \qquad \text{non-repetitive avalanche current} \qquad V_{sup} \leq 50 \text{ V; } V_{GS} = 10 \text{ V; } T_{j(init)} = 25 \text{ °C;} \qquad -35$	Avalanche ru	uggedness				
, to the same of t	E _{DS(AL)S}	•	$V_{sup} \le 50 \text{ V}$; unclamped; $t_p = 100 \text{ µs}$;	-	300	mJ
1163 = 00 11, 411014111904	I _{AS}	non-repetitive avalanche current	$V_{sup} \le 50 \text{ V; } V_{GS} = 10 \text{ V; } T_{j(init)} = 25 \text{ °C;}$ $R_{GS} = 50 \Omega; \text{ unclamped}$	-	35	Α

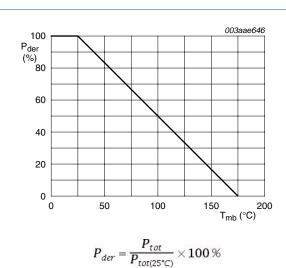


Fig 1. Normalized total power dissipation as a function of mounting base temperature

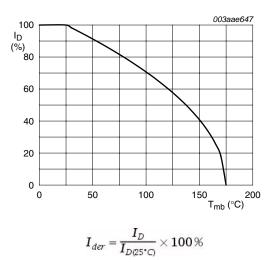


Fig 2. Normalized continuous drain current as a function of mounting base temperature

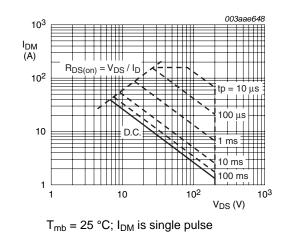


Fig 3. Safe operating area; continuous and peak drain currents as a function of drain-source voltage

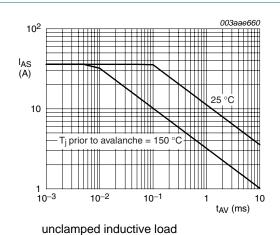


Fig 4. Single-shot avalanche rating; avalanche current as a function of avalanche period

5. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{th(j-mb)}$	thermal resistance from junction to mounting base		-	-	0.6	K/W
R _{th(j-a)}	thermal resistance from junction to ambient	minimum footprint ; FR4 board	-	50	-	K/W

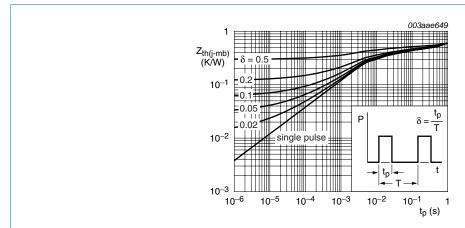


Fig 5. Transient thermal impedance from junction to mounting base as a function of pulse duration

6. Characteristics

Table 6. Characteristics

Table 6.	Characteristics					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	racteristics					
V _{(BR)DSS}	(BR)DSS drain-source breakdown	$I_D = 0.25 \text{ mA}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	200	-	-	V
voltage	$I_D = 0.25 \text{ mA}; V_{GS} = 0 \text{ V}; T_j = -55 \text{ °C}$	178	-	-	V	
V _{GS(th)}	gate-source threshold	$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = 175 \text{ °C}$	1	-	-	V
	voltage	$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_i = 25 \text{ °C}$	2	3	4	V
		$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = -55 \text{ °C}$	-	-	6	V
I _{DSS}	drain leakage current	$V_{DS} = 200 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 175 \text{ °C}$	-	-	500	μΑ
		V _{DS} = 200 V; V _{GS} = 0 V; T _i = 25 °C	-	0.03	10	μΑ
I _{GSS}	gate leakage current	V _{GS} = 10 V; V _{DS} = 0 V; T _j = 25 °C	-	2	100	nA
		$V_{GS} = -10 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	2	100	nA
R _{DSon}	drain-source on-state	$V_{GS} = 10 \text{ V}; I_D = 17 \text{ A}; T_j = 175 ^{\circ}\text{C}$	-	-	165	mΩ
resistance	V _{GS} = 10 V; I _D = 17 A; T _j = 25 °C	-	41	57	mΩ	
Dynamic (characteristics					
Q _{G(tot)}	total gate charge	$I_D = 39 \text{ A}; V_{DS} = 160 \text{ V}; V_{GS} = 10 \text{ V};$	-	96	-	nC
Q_{GS}	gate-source charge	T _j = 25 °C	-	13	-	nC
Q _{GD}	gate-drain charge		-	37	50	nC
C _{iss}	input capacitance	V _{DS} = 25 V; V _{GS} = 0 V; f = 1 MHz;	-	3750	-	pF
C _{oss}	output capacitance	T _j = 25 °C	-	385	-	pF
C _{rss}	reverse transfer capacitance		-	180	-	pF
t _{d(on)}	turn-on delay time	$V_{DS} = 100 \text{ V}; R_L = 2.7 \Omega; V_{GS} = 10 \text{ V};$	-	18	-	ns
t _r	rise time	$R_{G(ext)} = 5.6 \Omega$; $T_j = 25 ^{\circ}C$	-	58	-	ns
t _{d(off)}	turn-off delay time		-	105	-	ns
t _f	fall time		-	78	-	ns
L _D	internal drain inductance	measured from tab to centre of die ; $T_j = 25 ^{\circ}\text{C}$	-	3.5	-	nΗ
L _S	internal source inductance	measured from source lead to source bond pad; $T_j = 25$ °C	-	7.5	-	nΗ
Source-di	rain diode					
V_{SD}	source-drain voltage	$I_S = 25 \text{ A}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	0.85	1.2	V
t _{rr}	reverse recovery time	$I_S = 20 \text{ A}; dI_S/dt = -100 \text{ A/}\mu\text{s}; V_{GS} = 0 \text{ V};$	-	133	-	ns
Q _r	recovered charge	$V_{DS} = 30 \text{ V}; T_j = 25 ^{\circ}\text{C}$	-	895	-	nC

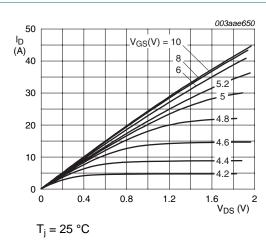


Fig 6. Output characteristics: drain current as a function of drain-source voltage; typical values

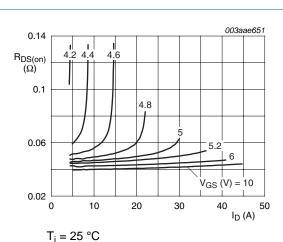


Fig 7. Drain-source on-state resistance as a function of drain current; typical values

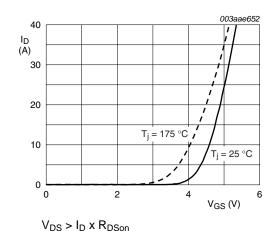


Fig 8. Transfer characteristics: drain current as a function of gate-source voltage; typical values

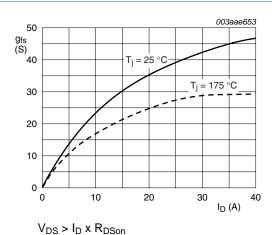


Fig 9. Forward transconductance as a function of drain current; typical values

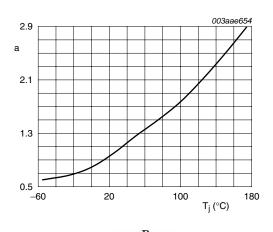


Fig 10. Normalized drain-source on-state resistance factor as a function of junction temperature

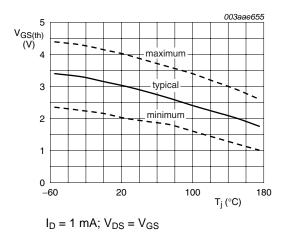


Fig 11. Gate-source threshold voltage as a function of junction temperature

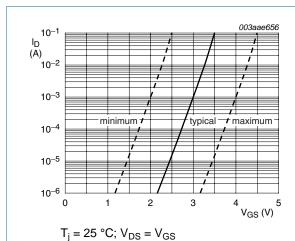
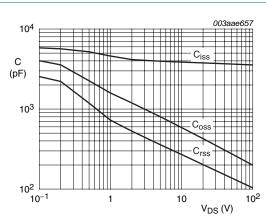
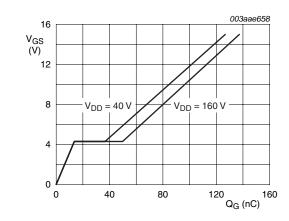


Fig 12. Sub-threshold drain current as a function of gate-source voltage



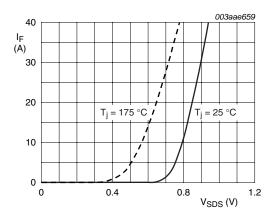
 $V_{GS} = 0 V$; f = 1 MHz

Fig 13. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values



 $T_j = 25 \, ^{\circ}\text{C}; I_D = 39 \, \text{A}$

Fig 14. Gate-source voltage as a function of gate charge; typical values



 $V_{GS} = 0 V$

Fig 15. Source (diode forward) current as a function of source-drain (diode forward) voltage; typical values

7. Package outline

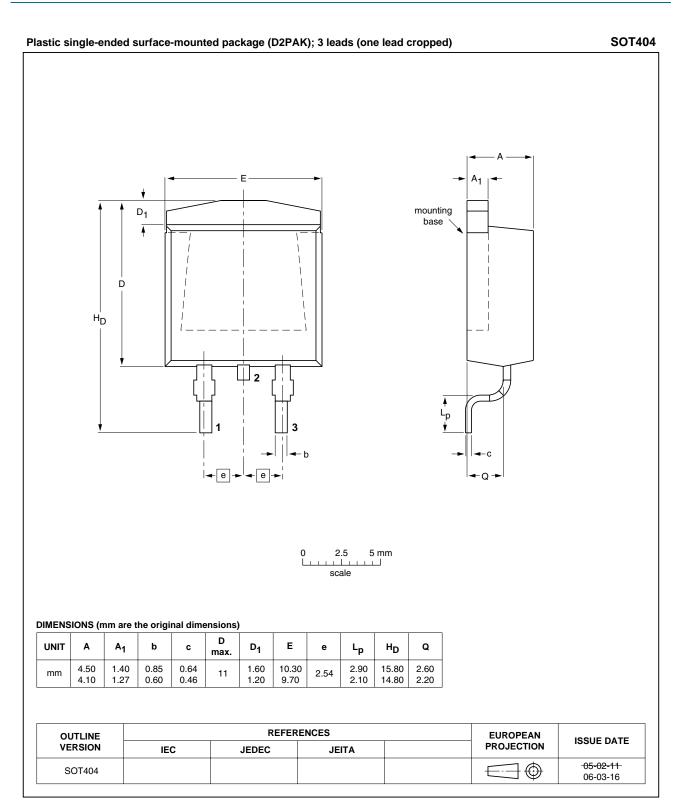


Fig 16. Package outline SOT404 (D2PAK)

8. Revision history

Table 7. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
PSMN057-200B v.2	20101214	Product data sheet	-	PSMN057-200B v.1
Modifications:		ormat of this data sheet has been redesigned to comply with the new identity guideling Semiconductors.		
	 Legal texts ha 	ve been adapted to the new	company name where	appropriate.
PSMN057-200B v.1	20001201	Product data sheet	-	-

9. Legal information

9.1 Data sheet status

Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
- [3] The product status of device(s) described in this document may have changed since this document was published and may differ in case of multiple devices. The latest product status information is available on the Internet at URL http://www.nxp.com.

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